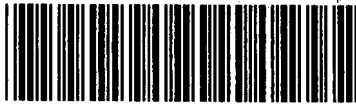


Search Notes

Application/Control No.

10/825,528

Examiner

Anthony Weier

Applicant(s)/Patent under
Reexamination

SHEN ET AL.

Art Unit

1794

SEARCHED

Class	Subclass	Date	Examiner
updated	previous search	10/9/2007	AW

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR